

Search Terms	
1	DISPLACEMENT
2	DISPLACEMENTS
3	DISTRIBUTION
4	DISTRIBUTIONS
5	ELECTRIC
6	ELECTRICS
7	ELECTROMAGNETIC
8	MAGNETIC
9	MAGNETICS
10	PROBE
11	PROBES
12	SAMPLED
13	SAMPLEDS
14	SAMPLER
15	SAMPLERS
16	SAMPLING
17	SAMPLINGS
18	SHIFT
19	SHIFTING
20	SHIFTINGS
21	SHIFTS
22	SPECTRUM
23	SPECTRUMS
24	SHIFTED
25	((SPECTRUM SAME SHIFT) AND ((SAMPLER OR SAMPLED OR SAMPLING) SAME PROBE)) AND ((DISTRIBUTION SAME (SHIFTED OR SHIFTING OR DISPLACEMENT OR SHIFT)) SAME (ELECTROMAGNETIC OR ELECTRIC OR MAGNETIC)))

	T	tal	USPAT	US-PGPUB	EPO	JPO	Derwent	IBM TDB	USOCR
1	568959								
2	48219								
3	856177								
4	54979								
5	3181797								
6	3699								
7	170								
8	1152972								
9	10688								
10	255258								
11	108114								
12	143047								
13	1								
14	20943								
15	3558								
16	238198								
17	4269								
18	569287								
19	283865								
20	614								
21	172030								
22	310891								
23	5747								
24	358284								
25	6	1	5	0	0	0	0	0	

	U	1	D	ocument ID	Issue Date	Pages	Title	Current OR
1	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 20030109997 A1	20030612	14	Field distribution measuring method and device	702/76
2	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 20030067312 A1	20030410		Voltage testing and measurement	324/753
3	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 20030057972 A1	20030327	60	Voltage testing and measurement	324/752
4	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 20030012733 A9	20030116		Method of using reduced dimensionality nuclear magnetic resonance spectroscopy for rapid chemical shift assignment and secondary structure determination of proteins	424/9.3
5	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 20020041850 A1	20020411		Method of using reduced dimensionality nuclear magnetic resonance spectroscopy for rapid chemical shift assignment and secondary structure determination of proteins	424/9.3
6	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 6512385 B1	20030128		Method for testing a device under test including the interference of two beams	324/753

Current XRef	Retrieval Classif	Inventor	S	C	P	2	3	4	5	Image Doc. Displayed	PT
1		Kitayoshi, Hitoshi	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20030109997						
2		Pfaff, Paul et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	
3		Pfaff, Paul et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 20030057972
4		Szyperski, Thomas A.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	
5		Szyperski, Thomas A.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	
6	324/752; 324/765	Pfaff, Paul et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	

Search Terms	
1	KITAYOSHI-HITOSHI
2	PROBE
3	PROBES
4	SHIFT
5	SHIFTING
6	SHIFTINGS
7	SHIFTS
8	SHIFTED
9	((KITAYOSHI-HITOSHI,IN,) AND PROBE) AND (SHIFTED OR SHIFTING OR SHIFT))

	T tal	USPAT	US-PGPUB	EPO	JPO	Derwent	IBM TDB	USOCR
<b>1</b>	105							
<b>2</b>	255258							
<b>3</b>	108114							
<b>4</b>	569287							
<b>5</b>	283865							
<b>6</b>	614							
<b>7</b>	172030							
<b>8</b>	358284							
<b>9</b>	4	2	1	1	0	0	0	

U	1	Document ID	Issue Date	Pages	Title	Current OR
1	<input checked="" type="checkbox"/>	□ US 20030109997 A1	20030612	14	Field distribution measuring method and device	702/76
2	<input checked="" type="checkbox"/>	□ US 5974178 A	19991026	19	Wavesource image visualization method using a partial division fast fourier transform	382/210
3	<input checked="" type="checkbox"/>	□ US 5656932 A	19970812		Non-contact type wave signal observation apparatus	324/615
4	<input checked="" type="checkbox"/>	□ EP 1191340 A1	20020327		FIELD DISTRIBUTION MEASURING METHOD AND DEVICE	

	Current XRef	Retrieval Classif	Invent r	S	C	P	2	3	4	5	Image D c. Displayed	PT
1	342/362;		Kitayoshi, Hitoshi	<input type="checkbox"/>	US 20030109997	<input type="checkbox"/>						
2	359/9, 382/280		Kitayoshi, Hitoshi	<input type="checkbox"/>	US 5974178	<input type="checkbox"/>						
3	324/630; 324/76.12		Kitayoshi, Hitoshi	<input type="checkbox"/>		<input type="checkbox"/>						
4			KITAYOSHI, HITOSHI	<input type="checkbox"/>		<input type="checkbox"/>						